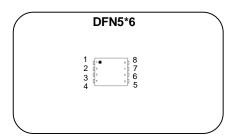


## N-channel Enhanced mode DFN5\*6 MOSFET

## **Features**

- High ruggedness
- Low  $R_{DS(ON)}$  (Typ  $9.9m\Omega$ )@ $V_{GS}$ =4.5V (Typ  $8.3m\Omega$ )@ $V_{GS}$ =10V
- Low Gate Charge (Typ 49nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: Electronic Ballast, Motor Control Synchronous Rectification, Inverter



4.Gate 5,6,7,8.Drain 1,2,3.Source

 $BV_{DSS}:60V$  $I_{D}:50A$ 

 $R_{DS(ON)}$ : 9.9m $\Omega@V_{GS}$ =4.5V

 $8.3 \text{m}\Omega@V_{GS}=10V$ 







## **General Description**

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.

### **Order Codes**

Item	Sales Type	Marking	Package	Packaging
1	SW HA 088R06VT	SW088R06VT	DFN5*6	REEL

## **Absolute maximum ratings**

Symbol	Parameter		Value	Unit
V <sub>DSS</sub>	Drain to source voltage		60	V
	Continuous drain current (@T <sub>C</sub> =25°C)	15	50*	А
l <sub>D</sub>	Continuous drain current (@T <sub>C</sub> =100°C)		33*	А
I <sub>DM</sub>	Drain current pulsed	(note 1)	200	А
	Continuous drain current (@T <sub>a</sub> =25°C)		13	А
I <sub>DSM</sub>	Continuous drain current (@T <sub>a</sub> =70°C)		10	А
V <sub>GS</sub>	Gate to source voltage		±20	V
E <sub>AS</sub>	Single pulsed avalanche energy	(note 2)	192	mJ
E <sub>AR</sub>	Repetitive avalanche energy	(note 1)	11	mJ
dv/dt	Peak diode recovery dv/dt	(note 3)	5	V/ns
	Total power dissipation (@T <sub>c</sub> =25°C)		40.3	W
P <sub>D</sub>	Total power dissipation (@T <sub>a</sub> =25°C)		2.8	W
T <sub>STG</sub> , T <sub>J</sub>	Operating junction temperature & storage ter	nperature	-55 ~ + 150	°C

<sup>\*.</sup> Drain current is limited by junction temperature.

## Thermal characteristics

Symbol	Parameter	Value	Unit
R <sub>thjc</sub>	Thermal resistance, Junction to case	3.1	°C/W
R <sub>thja</sub>	Thermal resistance, Junction to ambient	45	°C/W

Note:  $R_{thja}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is d efined as the solder mounting surface of the drain pins.  $R_{thjc}$  is guaranteed by design while  $R_{thca}$  is determined by the user's board design. DFN5\*6  $R_{thja}$ : 45 °C/W on a 1 in² pad of 2oz copper.



## **Electrical characteristic** ( $T_J = 25^{\circ}C$ unless otherwise specified )

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Off ch188a	racteristics					
BV <sub>DSS</sub>	Drain to source breakdown voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	60			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown voltage temperature coefficient	I <sub>D</sub> =250uA, referenced to 25°C		0.05		V/°C
	Drain to source leakage current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V			1	uA
I <sub>DSS</sub>		V <sub>DS</sub> =48V, T <sub>J</sub> =125°C			50	uA
	Gate to source leakage current, forward	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	(8		100	nA
$I_{GSS}$	Gate to source leakage current, reverse	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V			-100	nA
On charac	teristics				1	
V <sub>GS(TH)</sub>	Gate threshold voltage	$V_{DS}=V_{GS}$ , $I_{D}=250uA$	1.4		2.4	V
	Drain to source on state resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A,T <sub>J</sub> =25°C		9.9	12.4	mΩ
$R_{DS(ON)}$		V <sub>GS</sub> =10V, I <sub>D</sub> =5A,T <sub>J</sub> =25°C		8.3	10.4	mΩ
		V <sub>GS</sub> =10V, I <sub>D</sub> =5A,T <sub>J</sub> =125°C	4	13.3		mΩ
$G_fs$	Forward transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =5A	1	25		S
Dynamic c	haracteristics		).			
$C_{iss}$	Input capacitance			2010		pF
$C_{oss}$	Output capacitance	$V_{GS}$ =0V, $V_{DS}$ =30V, f=1MHz		207		
$C_{rss}$	Reverse transfer capacitance			165		
$t_{d(on)}$	Turn on delay time			12		ns
t <sub>r</sub>	Rising time	$V_{DS}$ =30V, $I_{D}$ =11A, $R_{G}$ =4.7 $\Omega$ , $V_{GS}$ =10V (note 4,5)		42		
t <sub>d(off)</sub>	Turn off delay time			45		
t <sub>f</sub>	Fall time	(11010-1,0)		20		
Qg	Total gate charge	V <sub>DS</sub> =48V, V <sub>GS</sub> =10V, I <sub>D</sub> =11A,		49		nC
$Q_gs$	Gate-source charge	I <sub>G</sub> =3mA		6		
$Q_{gd}$	Gate-drain charge	(note 4,5)		15		
$R_g$	Gate resistance	V <sub>DS</sub> =0V, Scan F mode		1.47		Ω

## Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Is	Continuous source current	Integral reverse p-n Junction			50	Α
I <sub>SM</sub>	Pulsed source current	diode in the MOSFET			200	Α
$V_{SD}$	Diode forward voltage drop.	I <sub>S</sub> =11A, V <sub>GS</sub> =0V			1.4	٧
t <sub>rr</sub>	Reverse recovery time	I <sub>S</sub> =11A, V <sub>GS</sub> =0V,		27		ns
Q <sub>rr</sub>	Reverse recovery charge	dI <sub>F</sub> /dt=100A/us		12		nC

- Repeatitive rating : pulse width limited by junction temperature.
- L =2.67mH,  $I_{AS}$  =12A,  $V_{DD}$ =50V,  $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$  = 25°C  $I_{SD}$  ≤ 11A, di/dt = 100A/us,  $V_{DD}$  ≤ BV<sub>DSS</sub>, Staring  $T_{J}$ =25°C Pulse Test : Pulse Width ≤ 300us, duty cycle ≤ 2%.
- 3.
- 4.
- Essentially independent of operating temperature.

Fig. 1. On-state characteristics

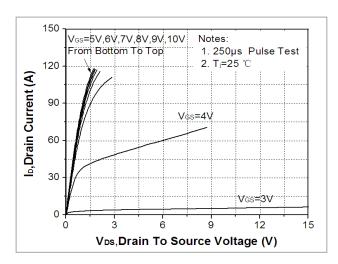


Fig. 3. On-resistance variation vs. drain current and gate voltage

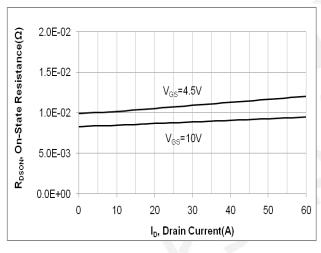


Fig. 5. Breakdown voltage variation vs. junction temperature

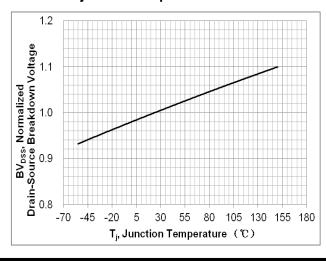


Fig. 2. Transfer characteristics

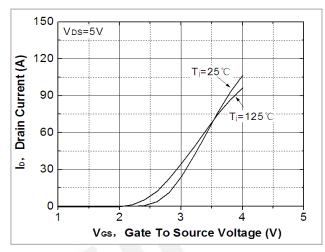


Fig. 4. On-state current vs. diode forward voltage

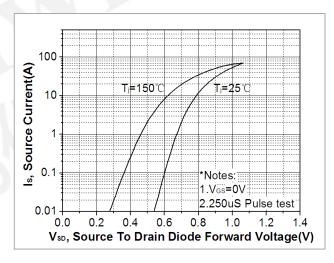


Fig. 6. On-resistance variation vs. junction temperature

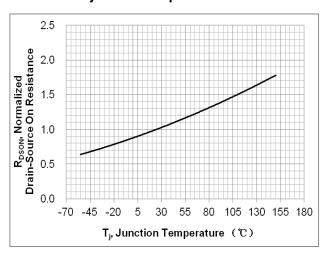


Fig. 7. Gate charge characteristics

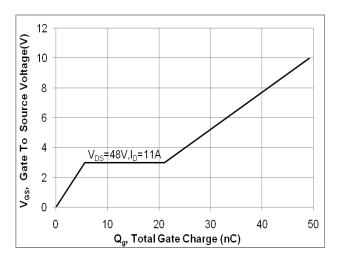


Fig. 9. Maximum safe operating area

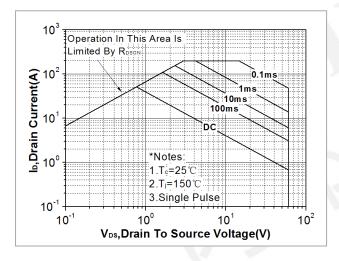


Fig. 8. Capacitance Characteristics

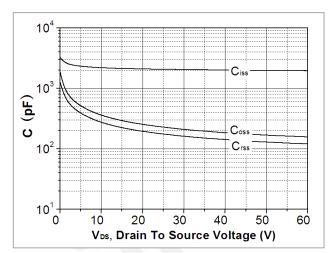


Fig. 10. Maximum drain current vs. case temperature

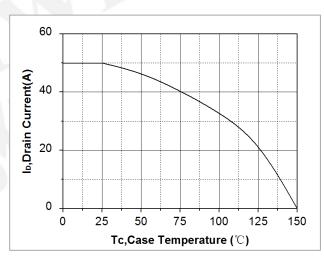


Fig. 11. Transient thermal response curve

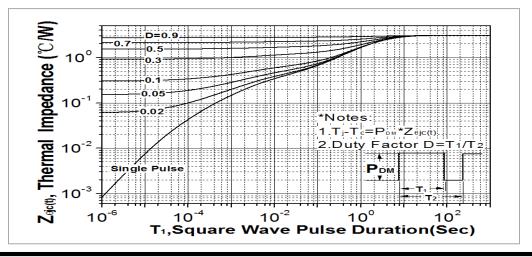




Fig. 12. Gate charge test circuit & waveform

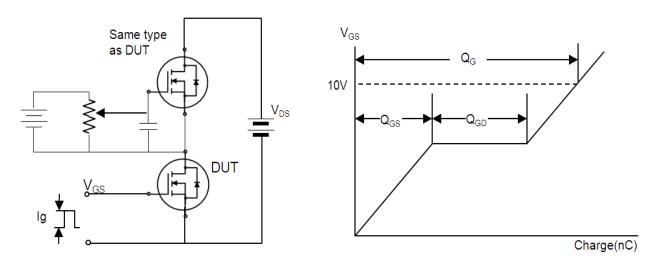


Fig. 13. Switching time test circuit & waveform

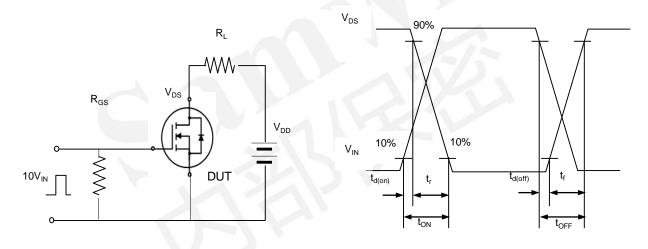


Fig. 14. Unclamped Inductive switching test circuit & waveform

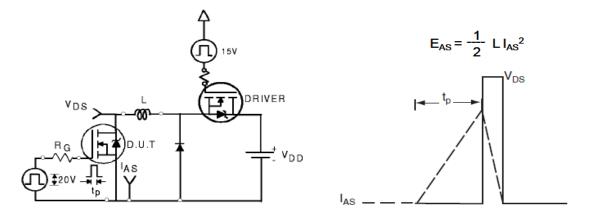
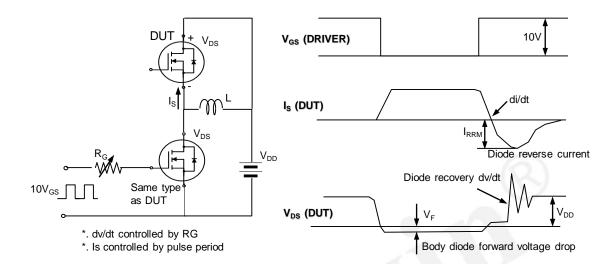




Fig. 15. Peak diode recovery dv/dt test circuit & waveform



## **DISCLAIMER**

- \* All the data & curve in this document was tested in XI'AN SEMIPOWER TESTING & APPLICATION CENTER.
- \* This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.
- \* Qualification standards can also be found on the Web site (http://www.semipower.com.cn)



\* Suggestions for improvement are appreciated, Please send your suggestions to samwin@samwinsemi.com

# **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for MOSFET category:

Click to view products by Sam&wing manufacturer:

Other Similar products are found below:

614233C 648584F MCH3443-TL-E MCH6422-TL-E NTNS3A92PZT5G IRFD120 IRFF430 JANTX2N5237 2N7000 AOD464
2SK2267(Q) 2SK2545(Q,T) 405094E 423220D MIC4420CM-TR VN1206L 614234A 715780A SSM6J414TU,LF(T 751625C
IPS70R2K0CEAKMA1 BSF024N03LT3 G PSMN4R2-30MLD TK31J60W5,S1VQ(O 2SK2614(TE16L1,Q) DMN1017UCP3-7
EFC2J004NUZTDG FCAB21350L1 P85W28HP2F-7071 DMN1053UCP4-7 NTE2384 NTE2969 NTE6400A DMC2700UDMQ-7
DMN2080UCB4-7 DMN61D9UWQ-13 US6M2GTR DMN31D5UDJ-7 SSM6P54TU,LF DMP22D4UFO-7B IPS60R3K4CEAKMA1
DMN1006UCA6-7 DMN16M9UCA6-7 STF5N65M6 IRF40H233XTMA1 IPSA70R950CEAKMA1 IPSA70R2K0CEAKMA1 STU5N65M6
C3M0021120D DMN6022SSD-13